

# Resource Summary Report

Generated by [dkNET](#) on Aug 6, 2026

## JEOL: JIB-4700F Focused Ion Beam

RRID:SCR\_020188

Type: Tool

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### Proper Citation

JEOL: JIB-4700F Focused Ion Beam (RRID:SCR\_020188)

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### Resource Information

**URL:** <https://www.jeolusa.com/PRODUCTS/Focused-Ion-Beam/JIB-4700F>

**Proper Citation:** JEOL: JIB-4700F Focused Ion Beam (RRID:SCR\_020188)

**Description:** Focused ion beam that can be used in morphological observations, elemental and crystallographic analyses of variety of specimens.

**Resource Type:** instrument resource

**Keywords:** Jeol, JEOL, Focused Ion Beam, Instrument Equipment, USEDit,

**Availability:** Commercially available

**Resource Name:** JEOL: JIB-4700F Focused Ion Beam

**Resource ID:** SCR\_020188

**Alternate IDs:** Model\_Number\_JIB-4700F

**Record Creation Time:** 20220129T080349+0000

**Record Last Update:** 20260801T190653+0000

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### Ratings and Alerts

No rating or validation information has been found for JEOL: JIB-4700F Focused Ion Beam.

No alerts have been found for JEOL: JIB-4700F Focused Ion Beam.

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### Data and Source Information

**Source:** [SciCrunch Registry](#)

## Usage and Citation Metrics

We have not found any literature mentions for this resource.